

© 2017 DeMille Research Inc. All rights reserved.

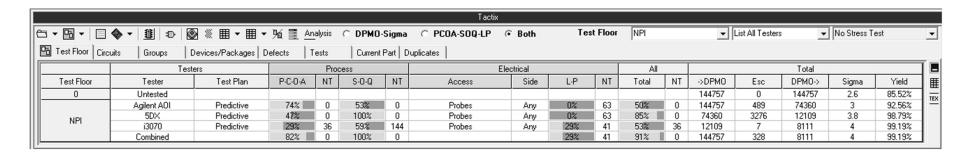
Overview

- Predictive test coverage analysis of the entire circuit board fault spectrum
- Combine ICT, Functional, Boundary Scan, XRay,
 Optical, and Visual test and inspection methods
- Determines the effectiveness and completeness of your overall test strategy prior to funding commitments

- Why Predictive Analysis?
 - Models the effectiveness of a test technology prior to development of the actual test
 - Reduces time and cost of overall test strategy
 - Employs advanced PCOA-SOQ-LP fault spectrum

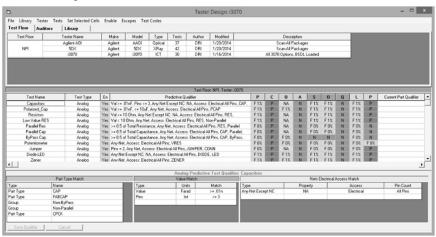
- The PCOA-SOQ-LP Fault Spectrum
 - Part process faults
 - P (Present), C (Correct), O (Orientation), and A (Alignment)
 - Pin process faults
 - S (Shorts), O (Opens), and Q (Quality)
 - Part electrical faults
 - L (Live) and P (Performance)

The Tactix Test Floor



- Choose any combination of testers
- Shows combined results of all tests

The Tester Library



- Uses an open, flexible rules-based model for fault analysis
- Includes a library of predefined Tester Models

© 2017 DeMille Research Inc. All rights reserved.

DeMille Research Inc.

25422 Trabuco Road, No. 105-247 Lake Forest, California 92630-2797

Phone: +1.949.462.9345

Fax: +1.949.462.9346

Email: salesinfo@testsight.com